



SLOVENSKI STANDARD
SIST EN 60679-4:2002
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Quartz crystal controlled oscillators of assessed quality - Part 4: Sectional specification - Capability approval (IEC 60679-4:1997)

Quartz crystal controlled oscillators of assessed quality -- Part 4: Sectional specification - Capability approval

Quarzoszillatoren mit bewerteter Qualität -- Teil 4: Rahmenspezifikation - Befähigungsanerkennung

Oscillateurs pilotés par quartz sous assurance de la qualité -- Partie 4: Spécification intermédiaire - Agrément de savoir-faire

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Ta slovenski standard je istoveten z: EN 60679-4:1998

ICS:

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EUROPEAN STANDARD
NORME EUROPÉENNE
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English version

**Quartz crystal controlled oscillators of assessed quality
Part 4: Sectional specification - Capability approval
(IEC 60679-4:1997)**

Oscillateurs pilotés par quartz sous
assurance de la qualité
Partie 4: Spécification intermédiaire
Agrément de savoir-faire
(CEI 60679-4:1997)

Quarzoszillatoren mit bewerteter
Qualität
Teil 4: Rahmenspezifikation
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(IEC 60679-4:1997)

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This European Standard was approved by CENELEC on 1998-01-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Czech Republic, Denmark, Finland, France, Germany, Greece, Iceland, Ireland, Italy, Luxembourg, Netherlands, Norway, Portugal, Spain, Sweden, Switzerland and United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Foreword

The text of document 49/386/FDIS, future edition 1 of IEC 60679-4, prepared by IEC TC 49, Piezoelectric and dielectric devices for frequency control and selection, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60679-4 on 1998-01-01.

This European Standard supersedes EN 169100:1993.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 1998-10-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) -

NOTE: The latest date of withdrawal will be fixed when all parts of EN 60679, which are to replace EN 169000 and its related specifications, are approved.

Annexes designated "normative" are part of the body of the standard.
In this standard, annexes A, B, C and ZA are normative.
Annex ZA has been added by CENELEC.

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Endorsement notice

The text of the International Standard IEC 60679-4:1997 was approved by CENELEC as a European Standard without any modification.



Annex ZA (normative)

Normative references to international publications
with their corresponding European publications

This European Standard incorporates by dated or undated reference, provisions from other publications. These normative references are cited at the appropriate places in the text and the publications are listed hereafter. For dated references, subsequent amendments to or revisions of any of these publications apply to this European Standard only when incorporated in it by amendment or revision. For undated references the latest edition of the publication referred to applies (including amendments).

NOTE: When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 61178-1	1993	Quartz crystal units - A specification in the IEC Quality Assessment System for electronic Components (IECQ) Part 1: Generic specification	-	-
IEC 60679-1	1997	Quartz crystal controlled oscillators of assessed quality Part 1: Generic specification	EN 60679-1	1998
IEC 60679-4-1	- ¹⁾	Part 4-1: Blank detail specification Capability approval	-	-

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1) To be published.

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**Oscillateurs pilotés par quartz sous assurance
de la qualité –**

**Partie 4:
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**Agrément de savoir-faire
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**Quartz crystal controlled oscillators
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**Part 4:
Sectional specification – Capability approval**

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International Electrotechnical Commission
Международная Электротехническая Комиссия

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For price, see current catalogue

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

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**QUARTZ CRYSTAL CONTROLLED OSCILLATORS
OF ASSESSED QUALITY –**
Part 4: Sectional specification – Capability approval

FOREWORD

- 1) The IEC (International Electrotechnical Commission) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of the IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, the IEC publishes International Standards. Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. The IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of the IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested National Committees.
- 3) The documents produced have the form of recommendations for international use and are published in the form of standards, technical reports or guides and they are accepted by the National Committees in that sense.
- 4) In order to promote international unification, IEC National Committees undertake to apply IEC International Standards transparently to the maximum extent possible in their national and regional standards. Any divergence between the IEC Standard and the corresponding national or regional standard shall be clearly indicated in the latter.
- 5) The IEC provides no marking procedure to indicate its approval and cannot be rendered responsible for any equipment declared to be in conformity with one of its standards.
- 6) Attention is drawn to the possibility that some of the elements of this International Standard may be the subject of patent rights. The IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 60679-4 has been prepared by IEC technical committee 49: Piezoelectric and dielectric devices for frequency control and selection.

This International Standard has been based on EN 169100: 1993, Quartz crystal controlled oscillators (Capability approval) of the CECC.

It forms part 4 of a series of standards for quartz crystal controlled oscillators and also constitutes a specification in the IEC Quality Assessment System for electronic components (IECQ) where it forms the sectional specification – Capability approval.

The text of this standard is based on the following documents:

FDIS	Report on voting
49/386/FDIS	49/390/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

IEC 60679 consists of the following parts under the general title Quartz controlled oscillators of assessed quality:

- Part 1: Generic specification (IEC 60679-1)
- Part 2: Guide to the use of quartz crystal controlled oscillators (IEC 60679-2)
- Part 3: Standard outlines and lead connections (IEC 60679-3)
- Part 4: Sectional specification – Capability approval (IEC 60679-4)
- Part 4-1: Blank detail specification – Capability approval (IEC 60679-4-1)
- Part 5: Sectional specification – Qualification approval (IEC 60679-5)
- Part 5-1: Blank detail specification – Qualification approval (IEC 60679-5-1)

The QC number which appears on the front cover of this publication is the specification number in the IEC Quality Assessment System for Electronic Components (IECQ).

Annexes A, B and C form an integral part of this standard.

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QUARTZ CRYSTAL CONTROLLED OSCILLATORS OF ASSESSED QUALITY –

Part 4: Sectional specification – Capability approval

1 General

1.1 Scope

This part of IEC 60679 applies to quartz crystal controlled oscillators as custom built products or as standard catalogue items and whose quality is assessed on the basis of capability approval.

It prescribes the preferred ratings and characteristics, with appropriate tests and measuring methods contained in the generic specification, IEC 60679-1, and gives the general performance requirements to be used in detail specifications for quartz crystal controlled oscillators.

The concept of preferred values is directly applicable to standard catalogue items but does not necessarily apply to custom built products.

1.2 Normative references

The following normative documents contain provisions which, through reference in this text, constitute provisions of this part of IEC 60679. At the time of publication, the editions indicated were valid. All normative documents are subject to revision, and parties to agreements based on this part of IEC 60679 are encouraged to investigate the possibility of applying the most recent editions of the normative documents indicated below. Members of IEC and ISO maintain registers of currently valid International Standards.

IEC 61178-1:1993, *Quartz crystal units – A specification in the IEC quality assessment system for electronic components (IECQ) – Part 1: Generic specification*

IEC 60679-1:1997, *Quartz crystal controlled oscillators of assessed quality – Part 1: Generic specification*

IEC 60679-4-1– *Quartz crystal controlled oscillators of assessed quality – Part 4-1: Blank detail specification – Capability approval*¹⁾

2 Preferred values for ratings and guidance on detail specifications

2.1 Preferred values for ratings and characteristics

The values given in detail specifications shall preferably be selected from those stated in 2.3 of the generic specification IEC 60679-1.

¹⁾ To be published.

2.2 Information to be prescribed in detail specifications

(Applies to both custom built and standard catalogue items.)

Guidance on the preparation of detail specifications is given in the future blank detail specification, IEC 60679-4-1.

Each detail specification shall state all the tests and measurements required for inspection. For standard catalogue items this shall, as a minimum, include the relevant tests given in the blank detail specification, with methods and severities.

The following information shall be given in each detail specification.

2.2.1 Outline drawing and dimensions

The detail specification shall include a dimensional drawing of the crystal controlled oscillator, and/or reference to an appropriate international standard, to permit easy recognition and to provide information for dimensioning and gauging procedures.

The dimensions shall include the overall dimensions of the body of the component, and the size and spacing of the terminations. All dimensions shall be stated in millimetres.

Terminal connections shall be identified for all enclosures.

When a detail specification covers more than one enclosure, the dimensions and their associated tolerances shall be placed in a table below the drawing.

When the configuration is other than described above, the detail specification shall state such dimensional information as will adequately describe the crystal controlled oscillator.

2.2.2 Marking

The detail specification shall prescribe the content of the marking on the crystal controlled oscillator and on the primary package in accordance with 2.4 of IEC 60679-1.

2.2.3 Ordering information

The detail specification shall prescribe that the following information is required when ordering a crystal controlled oscillator:

- a) quantity;
- b) detail specification number, issue number and date, and where applicable;
- c) type of oscillator (e.g. SPXO, VCXO, TCXO, etc.);
- d) nominal frequency in kilohertz or megahertz;
- e) frequency tolerance(s) and operating temperature range;
- f) full description of any additional requirements to identify the oscillator.